IN THE CLAIMS

Please amend the claims as follows:

1. (Cancelled).

2. (Currently Amended) ~~Method~~ A method of ~~monitoring the operational temperature of~~operating a disc drive having a semi-conductor laser device ~~(3) in a disc drive (1)~~, the method comprising the steps of:

applying electrical power to said semi-conductor laser device ~~(3)~~;

measuring a light intensity ~~(Iout)~~ of a laser beam ~~(4)~~ generated by said semi-conductor laser device ~~(20)~~;

controlling said electrical power such that said light intensity ~~(Iout)~~ remains constant;

measuring at least one electrical parameter (VCL; I) indicative of the work point (W) of said semi-conductor laser ~~(20)~~device; and

~~and~~ determining ~~said~~ an operational temperature of said semi-conductor laser device on the basis of a predetermined relationship between said work point ~~(W) on the one hand~~ and said operational temperature ~~on the other hand~~.

3. (Currently Amended) ~~Method~~ The method of operating a disc drive ~~which comprises a semi conductor laser device (3)~~as claimed

in claim 2, wherein the method ~~comprising further comprises~~ the ~~steps~~ step of:

~~applying electrical power to said semi conductor laser device (3),~~

~~measuring a light intensity (Lout) of a laser beam (4) generated by said semi conductor laser device (20),~~

~~controlling said electrical power such that said light intensity (Lout) remains constant,~~

~~measuring at least one electrical parameter (VCL, I) indicative of the work point (W) of said semi conductor laser (20),~~

~~and~~ taking temperature reducing steps if the measured value of said at least one electrical parameter ~~(VCL, I)~~ indicates that the operational temperature of the laser device has reached a predetermined critical temperature ~~(TCRIT)~~.

4. (Currently Amended) ~~Method according to~~The method as claimed in claim 3,

wherein said step of measuring at least one electrical parameter comprises measuring a plurality of electrical parameters ~~(VCL, I)~~ indicative of the work point ~~(W)~~ of said semi-conductor laser ~~(20) are measured,~~device,

and wherein said temperature reducing steps are taken if at least one of said plurality of electrical parameters indicates that the operational temperature of the laser device has reached a predetermined critical temperature ~~(TCRIT)~~.

5. (Currently Amended) ~~Method according to~~The method as claimed in claim 3 ~~or 4~~, wherein ~~an~~ the at least one electrical parameter ~~(VCL)~~ is compared with a predetermined parameter level ~~(VCRIT, VNORM)~~.

6. (Currently Amended) ~~Method according to~~ The method as claimed in claim 5,

wherein said electrical parameter ~~(VCL)~~ is measured at a certain known temperature of the laser device, this measured value being taken as zero value ~~(V0)~~,

wherein said electrical parameter ~~(VCL)~~ is measured during operation of the disc drive to yield an actual value ~~(VCL)~~,

and wherein the difference ~~(ΔV)~~ between the actual value of said electrical parameter ~~(VCL)~~ and said zero value ~~(V0)~~ is compared with a predetermined threshold.

7. (Currently Amended) ~~Method according to any of claims 3-6~~The method as claimed in any one of claims 3-6, wherein said temperature reducing steps comprise, ~~for instance,~~ the step of operating a cooling device or a ventilator, or the step of reducing a clock frequency, or the step of reducing a rotational speed of a motor ~~(2)~~ of said disc drive ~~(1)~~.

8. (Currently Amended) ~~Method according to~~ The method as claimed in claim 7, wherein ~~a~~ the rotational speed of ~~a~~ the motor ~~(2)~~ of said disc drive ~~(1)~~ is reduced when said electrical

parameter ~~(VCL)~~ reaches a first predetermined parameter level ~~(VCRIT)~~ indicative of said semi-conductor laser device ~~(20)~~ having reached a predetermined critical temperature ~~(TCRIT)~~, and wherein the rotational speed of said motor ~~(2)~~ of said disc drive ~~(1)~~ is increased when said electrical parameter ~~(VCL)~~ reaches a second predetermined parameter level ~~(VNORM)~~ indicative of said semi-conductor laser device ~~(20)~~ having reached a normal temperature.

9. (Currently Amended) ~~Disc~~ A disc drive ~~(1),~~ comprising:

a disc drive motor ~~(2)~~ for rotating an optical disc ~~(10)~~;

a laser device ~~(3)~~ for generating a laser beam ~~(4)~~ for scanning the optical disc; and

a control unit ~~(5)~~ for controlling the disc drive motor ~~(2)~~ and the laser device ~~(3)~~;,

wherein the control unit ~~(5) is designed to monitor~~ monitors at least one electrical parameter ~~(VCL; I)~~ indicative of ~~the~~ a work point ~~(W)~~ of a semi-conductor laser ~~(20)~~ of said laser device ~~(3)~~, and ~~to take~~ takes laser device temperature affecting steps in ~~dependency of~~ dependence on said at least one electrical parameter ~~(VCL; I)~~.

10. (Currently Amended) ~~Disc~~ The disc drive ~~according to~~ as claimed in claim 9, wherein the control unit ~~(5) is designed to control~~ controls the rotational speed of said disc drive motor ~~(2)~~ in ~~dependency of~~ dependence on said at least one electrical parameter ~~(VCL; I)~~.

11. (Currently Amended) ~~Disc~~ The disc drive ~~according to~~as claimed in claim 9 or 10, wherein said disc drive further ~~comprising~~comprises:

a light intensity sensor ~~(7)~~ coupled to an input ~~(8)~~ of the control unit ~~(5)~~, ~~disposed to receive~~said light intensity sensor receiving at least a portion of the laser beam ~~(4)~~ generated by the semi-conductor laser ~~(20)~~, ~~and designed to generate~~said light intensity sensor generating a measuring signal ~~(S)~~ representative of the light intensity of said laser beam ~~(4)~~;

the control unit ~~(5) being designed to control~~controlling said semi-conductor laser ~~(20)~~in response to said measuring signal such as to maintain a constant laser beam intensity.

12. (Currently Amended) ~~Disc~~ The disc drive ~~according to~~as claimed in claim 11, wherein said at least one electrical parameter ~~(VCL, I)~~ comprises an output voltage ~~(VCL)~~ of the control unit ~~(5)~~.

13. (Currently Amended) ~~Disc~~ The disc drive ~~according to~~as claimed in claim 11, wherein said at least one electrical parameter comprises ~~the~~ a difference ~~(ΔV)~~ between ~~the~~ an actual value of ~~an~~ the output voltage ~~(VCL)~~ of the control unit ~~(5)~~ and a zero value ~~(V0)~~ of said output voltage ~~(VCL)~~ of the control unit ~~(5)~~ measured at a certain known temperature of the laser device.

14. (Currently Amended) ~~Disc~~ The disc drive ~~according to any of claims 9-13~~as claimed in claim 9, wherein said disc drive comprises~~comprising~~ a plurality of semi-conductor lasers ~~(20A, 20B)~~;

wherein the control unit ~~(5)~~ has a plurality of outputs ~~(6A, 6B)~~ each providing a corresponding control signal ~~(VCL,A, VCL,B)~~ to a corresponding one of said semi-conductor lasers ~~(20A, 20B)~~;

and wherein the control unit ~~(5) is designed to~~ ~~monitor~~monitors a single signal indicative of a work point of only one of said semi-conductor lasers ~~(20A, 20B)~~, and ~~to take~~takes laser device temperature affecting steps in ~~dependency of~~dependence on said single threshold voltage indicating signal.

15. (Cancelled).